IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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IN A WAFER

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Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

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GROUP 2800

Associate Power of Attorney

I hereby appoint as associate attorneys of record all of the attorneys and agents at Customer Number 25962.

Also please direct all future correspondence to:

Ira S. Matsil Slater & Matsil, L.L.P. 17950 Preston Road, Suite 1000 Dallas, TX 75252 (972) 732-1001 (972) 732-9218 (fax)

Respectfully submitted,

Stanton C. Braden Attorney for Applicants

Reg. No. 32,556

Infineon Technologies North America Corp. Intellectual Property Department, 5th Floor 170 Wood Avenue S. Iselin, NJ 08830